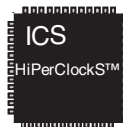


## General Description



The ICS840004I is a 4 output LVCMOS/LVTTL Synthesizer optimized to generate Fibre Channel reference clock frequencies and is a member of the HiPerClocks™ family of high performance clock solutions from IDT. Using a 26.5625MHz or a 26.04166MHz, 18pF parallel resonant crystal, the following frequencies can be generated based on the 2 frequency select pins (F\_SEL1:0): 212.5MHz, 159.375MHz, 156.25MHz, 106.25MHz, and 53.125MHz. The ICS840004I uses IDT's 3<sup>rd</sup> generation low phase noise VCO technology and can achieve 1ps or lower typical random rms phase jitter, easily meeting Fibre Channel jitter requirements. The ICS840004I is packaged in a small 20-pin TSSOP package.

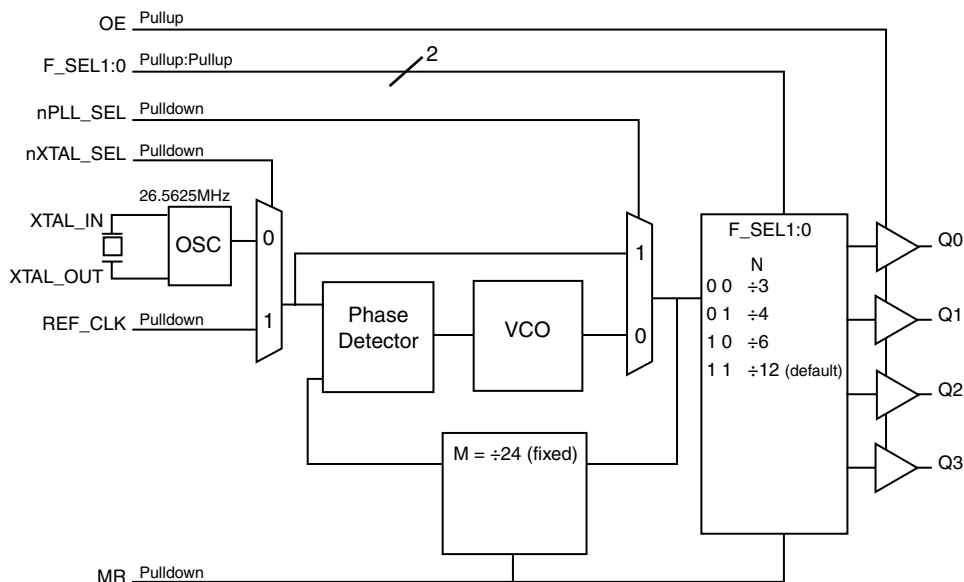
## Features

- Four single-ended LVCMOS/LVTTL outputs  
17Ω typical output impedance
- Selectable crystal oscillator interface or single-ended input
- Supports the following output frequencies: 212.5MHz, 159.375MHz, 156.25MHz, 106.25MHz and 53.125MHz
- VCO range: 560MHz - 700MHz
- RMS phase jitter at 212.5MHz (637kHz – 10MHz):  
0.49ps (typical)
- Output supply modes:  
Core/Output  
3.3V/3.3V  
3.3V/2.5V  
2.5V/2.5V
- -40°C to 85°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

### Frequency Select Function Table

Inputs						Output Frequency Range (MHz)
Input Frequency (MHz)	F_SEL1	F_SEL0	M Divider Value	N Divider Value	M/N Ratio Value	
26.5625	0	0	24	3	8	212.5
26.5625	0	1	24	4	6	159.375
26.5625	1	0	24	6	4	106.25
26.5625	1	1	24	12	2	53.125 (default)
26.04166	0	1	24	4	6	156.25

## Block Diagram



## Pin Assignment

F_SEL0	1	20	F_SEL1
nc	2	19	GND
nXTAL_SEL	3	18	Q0
REF_CLK	4	17	Q1
OE	5	16	V <sub>DDO</sub>
MR	6	15	Q2
nPLL_SEL	7	14	Q3
V <sub>DDA</sub>	8	13	GND
nc	9	12	XTAL_IN
V <sub>DD</sub>	10	11	XTAL_OUT

ICS840004I

## 20-Lead TSSOP

**6.5mm x 4.4mm x 0.925mm**  
**package body**  
**G Package**  
**Top View**

**Table 1. Pin Descriptions**

Number	Name	Type		Description
1, 20	F_SELO, F_SEL1	Input	Pullup	Frequency select pins. LVCMOS/LVTTL interface levels.
2, 9	nc	Unused		No connect.
3	nXTAL_SEL	Input	Pulldown	Selects between the crystal or REF_CLK inputs as the PLL reference source. When HIGH, selects REF_CLK. When LOW, selects XTAL inputs. LVCMOS/LVTTL interface levels.
4	REF_CLK	Input	Pulldown	Single-ended reference clock input. LVCMOS/LVTTL interface levels.
5	OE	Input	Pullup	Output enable pin. When HIGH, the outputs are active. When LOW, the outputs are in a high impedance state. LVCMOS/LVTTL interface levels.
6	MR	Input	Pulldown	Active HIGH Master Reset. When logic HIGH, the internal dividers are reset causing the outputs to go low. When logic LOW, the internal dividers and the outputs are enabled. LVCMOS/LVTTL interface levels.
7	nPLL_SEL	Input	Pulldown	PLL bypass. When LOW, the output is driven from the VCO output. When HIGH, the PLL is bypassed and the output frequency = reference clock frequency/N output divider. LVCMOS/LVTTL interface levels.
8	V <sub>DDA</sub>	Power		Analog supply pin.
10	V <sub>DD</sub>	Power		Core supply pin.
11, 12	XTAL_OUT, XTAL_IN	Input		Crystal oscillator interface. XTAL_IN is the input. XTAL_OUT is the output.
13, 19	GND	Power		Power supply ground.
14, 15, 17, 18	Q3, Q2, Q1, Q0	Output		Single-ended clock outputs. 17Ω typical output impedance. LVCMOS/ LVTTL interface levels.
16	V <sub>DDO</sub>	Power		Output supply pin.

NOTE: *Pullup and Pulldown* refer to internal input resistors. See Table 2, *Pin Characteristics*, for typical values.

**Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			4		pF
C <sub>PD</sub>	Power Dissipation Capacitance			8		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			51		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			51		kΩ
R <sub>OUT</sub>	Output Impedance	V <sub>DDO</sub> = 3.3V±5%		17		Ω
		V <sub>DDO</sub> = 2.5V±5%		21		Ω

## Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, $V_{DD}$	4.6V
Inputs, $V_I$	-0.5V to $V_{DD} + 0.5V$
Outputs, $V_O$	-0.5V to $V_{DDO} + 0.5V$
Package Thermal Impedance, $\theta_{JA}$	73.2°C/W (0 lfpm)
Storage Temperature, $T_{STG}$	-65°C to 150°C

## DC Electrical Characteristics

**Table 3A. Power Supply DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDO} = 3.3V \pm 5\%$  or  $2.5V \pm 5\%$ ,  $T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Core Supply Voltage		3.135	3.3	3.465	V
$V_{DDA}$	Analog Supply Voltage		3.135	3.3	3.465	V
$V_{DDO}$	Output Supply Voltage		3.135	3.3	3.465	V
			2.375	2.5	2.625	V
$I_{DD}$	Power Supply Current				100	mA
$I_{DDA}$	Analog Supply Current				12	mA
$I_{DDO}$	Output Supply Current				10	mA

**Table 3B. Power Supply DC Characteristics,  $V_{DD} = 2.5V \pm 5\%$ ,  $V_{DDO} = 2.5V \pm 5\%$ ,  $T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Core Supply Voltage		2.375	2.5	2.625	V
$V_{DDA}$	Analog Supply Voltage		2.375	2.5	2.625	V
$V_{DDO}$	Output Supply Voltage		2.375	2.5	2.625	V
$I_{DD}$	Power Supply Current				95	mA
$I_{DDA}$	Analog Supply Current				12	mA
$I_{DDO}$	Output Supply Current				8	mA

**Table 3C. LVCMOS/LVTTL DC Characteristics,  $T_A = -40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$** 

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
$V_{IH}$	Input High Voltage		$V_{DD} = 3.465\text{V}$	2		$V_{DD} + 0.3$	V
			$V_{DD} = 2.625\text{V}$	1.7		$V_{DD} + 0.3$	V
$V_{IL}$	Input Low Voltage		$V_{DD} = 3.465\text{V}$	-0.3		0.8	V
			$V_{DD} = 2.625\text{V}$	-0.3		0.7	V
$I_{IH}$	Input High Current	nXTAL_SEL, nPLL_SEL, REF_CLK, MR	$V_{DD} = V_{IN} = 3.465\text{V}$ or $2.625\text{V}$			150	$\mu\text{A}$
		OE, F_SEL[0:1]	$V_{DD} = V_{IN} = 3.465\text{V}$ or $2.625\text{V}$			5	$\mu\text{A}$
$I_{IL}$	Input Low Current	nXTAL_SEL, nPLL_SEL, REF_CLK, MR	$V_{DD} = 3.465\text{V}$ or $2.625\text{V}$ , $V_{IN} = 0\text{V}$	-5			$\mu\text{A}$
		OE, F_SEL[0:1]	$V_{DD} = 3.465\text{V}$ or $2.625\text{V}$ , $V_{IN} = 0\text{V}$	-150			$\mu\text{A}$
$V_{OH}$	Output High Voltage; NOTE 1		$V_{DDO} = 3.3\text{V} \pm 5\%$	2.6			V
			$V_{DDO} = 2.5\text{V} \pm 5\%$	1.8			V
$V_{OL}$	Output Low Voltage; NOTE 1		$V_{DDO} = 3.3\text{V} \pm 5\%$ or $2.5\text{V} \pm 5\%$			0.5	V

NOTE 1: Outputs terminated with  $50\Omega$  to  $V_{DDO}/2$ . See Parameter Measurement Information section. *Load Test Circuit diagrams.*

**Table 4. Crystal Characteristics**

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation		Fundamental			
Frequency			26.5625		MHz
Equivalent Series Resistance (ESR)				50	$\Omega$
Shunt Capacitance				7	pF
Drive Level				1	mW

## AC Electrical Characteristics

**Table 5A. AC Characteristics,  $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$f_{out}$	Output Frequency	$F\_SEL[1:0] = 00$	186.67	212.5	226.66	MHz
		$F\_SEL[1:0] = 01$	140	159.375	170	MHz
		$F\_SEL[1:0] = 10$	93.33	106.25	113.33	MHz
		$F\_SEL[1:0] = 11$	46.67	53.125	56.66	MHz
$t_{sk(o)}$	Output Skew: NOTE 1, 2				60	MHz
$t_{jit}(\emptyset)$	RMS Phase Jitter (Random); NOTE 3	212.5MHz, Integration Range: 637kHz – 10MHz		0.49		ps
		159.375MHz, Integration Range: 637kHz – 10MHz		0.55		ps
		156.25MHz, Integration Range: 1.875MHz – 20MHz		0.56		ps
		106.25MHz, Integration Range: 637kHz – 10MHz		0.79		ps
		53.125MHz, Integration Range: 637kHz – 10MHz		0.65		ps
$t_R / t_F$	Output Rise/Fall Time	20% to 80%	250		800	ps
odc	Output Duty Cycle	$F\_SEL[1:0] = 00$	40		60	%
		$F\_SEL[1:0] = 01$	42		58	%
		$F\_SEL[1:0] = 10$ or $11$	48		52	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at  $V_{DDO}/2$ .

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Please refer to the Phase Noise Plot.

**Table 5B. AC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $V_{DDO} = 2.5V \pm 5\%$ ,  $T_A = -40^\circ C$  to  $85^\circ C$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$f_{out}$	Output Frequency	F_SEL[1:0] = 00	186.67	212.5	226.66	MHz
		F_SEL[1:0] = 01	140	159.375	170	MHz
		F_SEL[1:0] = 10	93.33	106.25	113.33	MHz
		F_SEL[1:0] = 11	46.67	53.125	56.66	MHz
$t_{sk(o)}$	Output Skew: NOTE 1, 2				60	MHz
$t_{jit}(\emptyset)$	RMS Phase Jitter (Random); NOTE 3	212.5MHz, Integration Range: 637kHz – 10MHz		0.46		ps
		159.375MHz, Integration Range: 637kHz – 10MHz		0.54		ps
		156.25MHz, Integration Range: 1.875MHz – 20MHz		0.57		ps
		106.25MHz, Integration Range: 637kHz – 10MHz		0.73		ps
		53.125MHz, Integration Range: 637kHz – 10MHz		0.63		ps
$t_R / t_F$	Output Rise/Fall Time	20% to 80%	250		800	ps
odc	Output Duty Cycle	F_SEL[1:0] = 00	40		60	%
		F_SEL[1:0] = 01	42		58	%
		F_SEL[1:0] = 10 or 11	48		52	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at  $V_{DDO}/2$ .

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Please refer to the Phase Noise Plot.

**Table 5C. AC Characteristics,  $V_{DD} = V_{DDO} = 2.5V \pm 5\%$ ,  $T_A = -40^\circ\text{C}$  to  $85^\circ\text{C}$** 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$f_{out}$	Output Frequency	F_SEL[1:0] = 00	186.67	212.5	226.66	MHz
		F_SEL[1:0] = 01	140	159.375	170	MHz
		F_SEL[1:0] = 10	93.33	106.25	113.33	MHz
		F_SEL[1:0] = 11	46.67	53.125	56.66	MHz
$t_{sk(o)}$	Output Skew: NOTE 1, 2				60	MHz
$t_{jit}(\emptyset)$	RMS Phase Jitter (Random); NOTE 3	212.5MHz, Integration Range: 637kHz – 10MHz		0.51		ps
		159.375MHz, Integration Range: 637kHz – 10MHz		0.51		ps
		156.25MHz, Integration Range: 1.875MHz – 20MHz		0.54		ps
		106.25MHz, Integration Range: 637kHz – 10MHz		0.72		ps
		53.125MHz, Integration Range: 637kHz – 10MHz		0.71		ps
$t_R / t_F$	Output Rise/Fall Time	20% to 80%	250		800	ps
odc	Output Duty Cycle	F_SEL[1:0] = 00	40		60	%
		F_SEL[1:0] = 01	42		58	%
		F_SEL[1:0] = 10 or 11	48		52	%

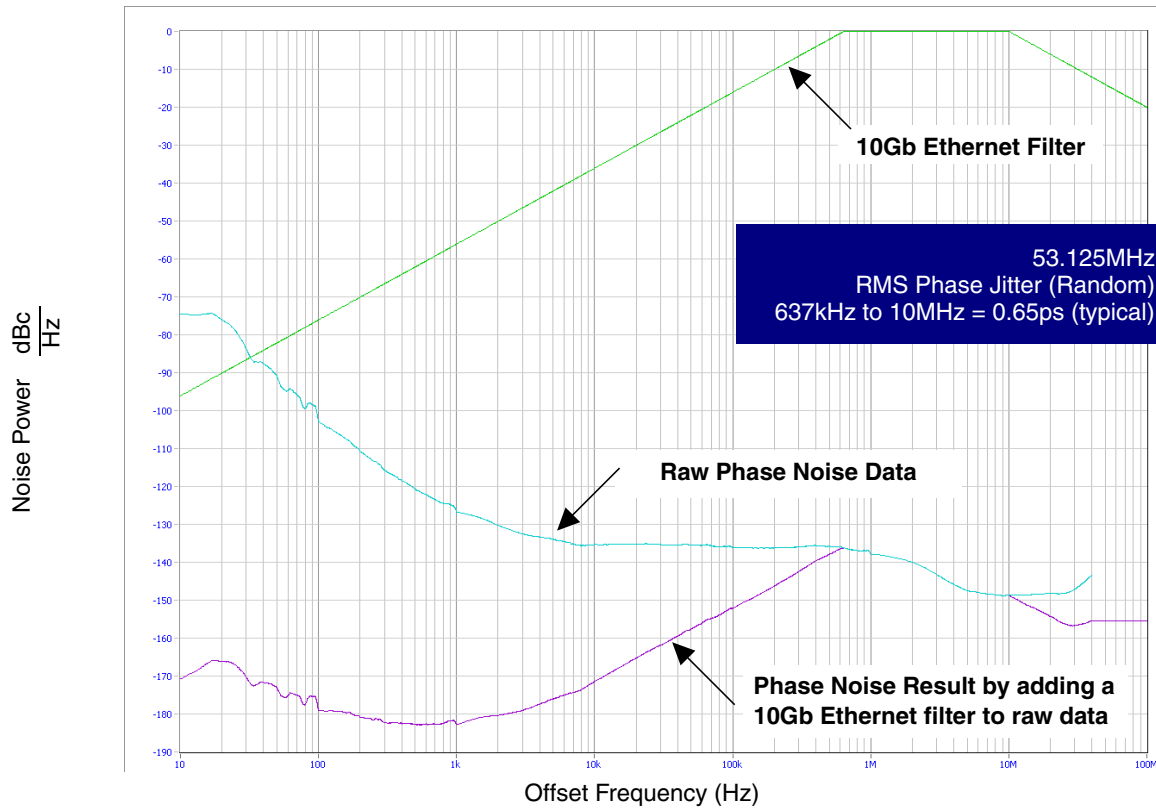
NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at  $V_{DDO}/2$ .

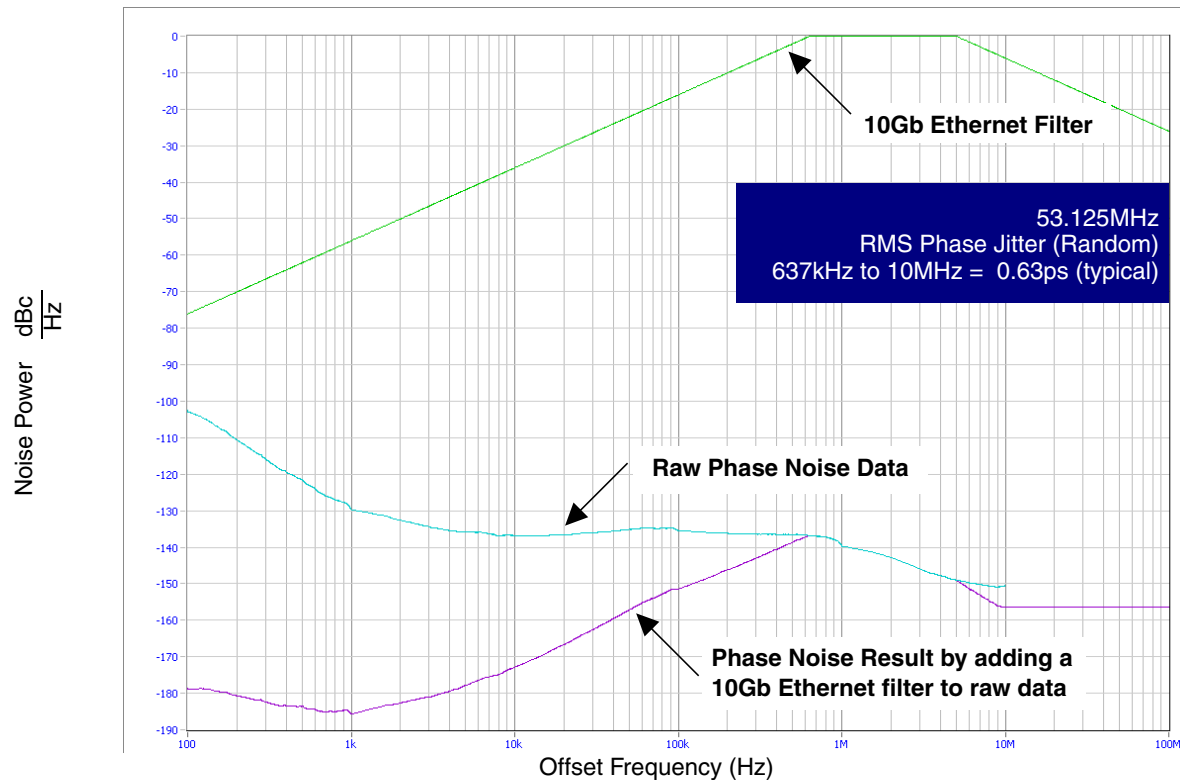
NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Please refer to the Phase Noise Plot.

## Typical Phase Noise at 53.125MHz ( $V_{DD} = V_{DDO} = 3.3V$ )

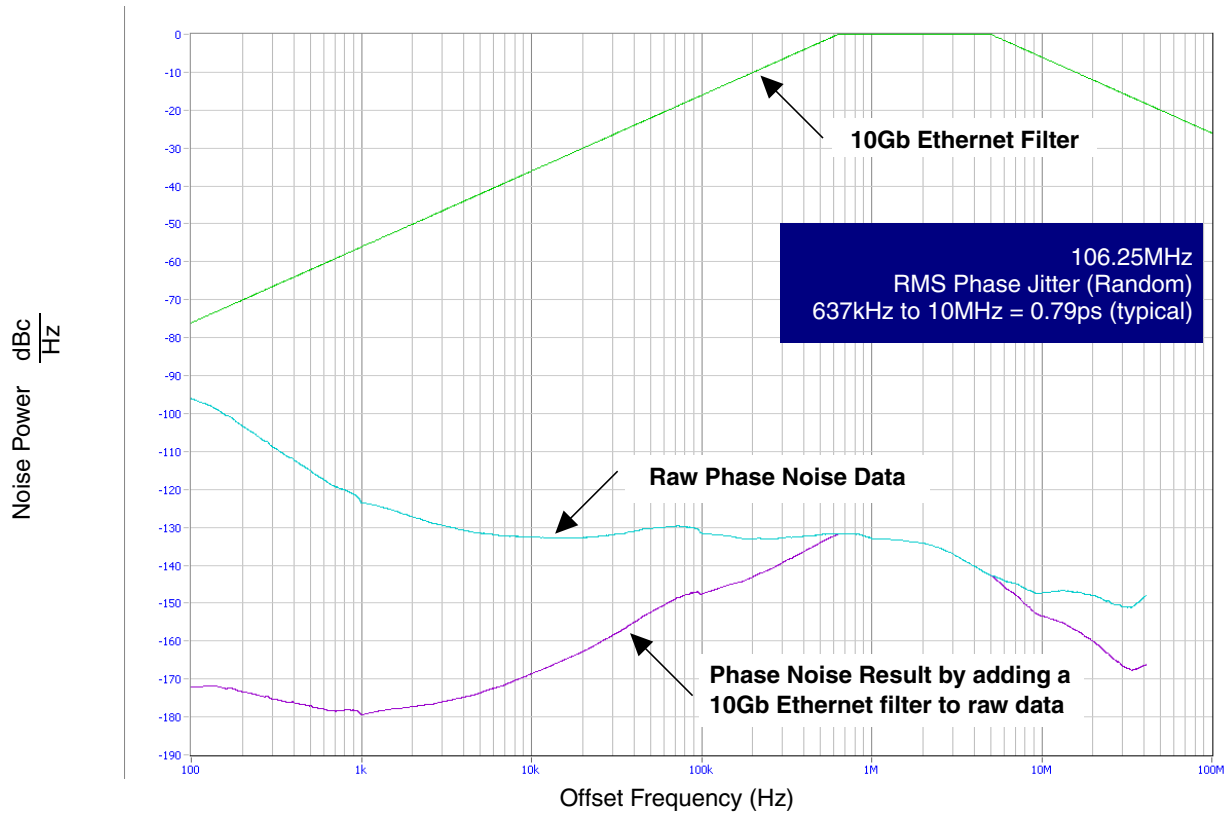


## Typical Phase Noise at 53.125MHz ( $V_{DD} = 3.3V, V_{DDO} = 2.5V$ )

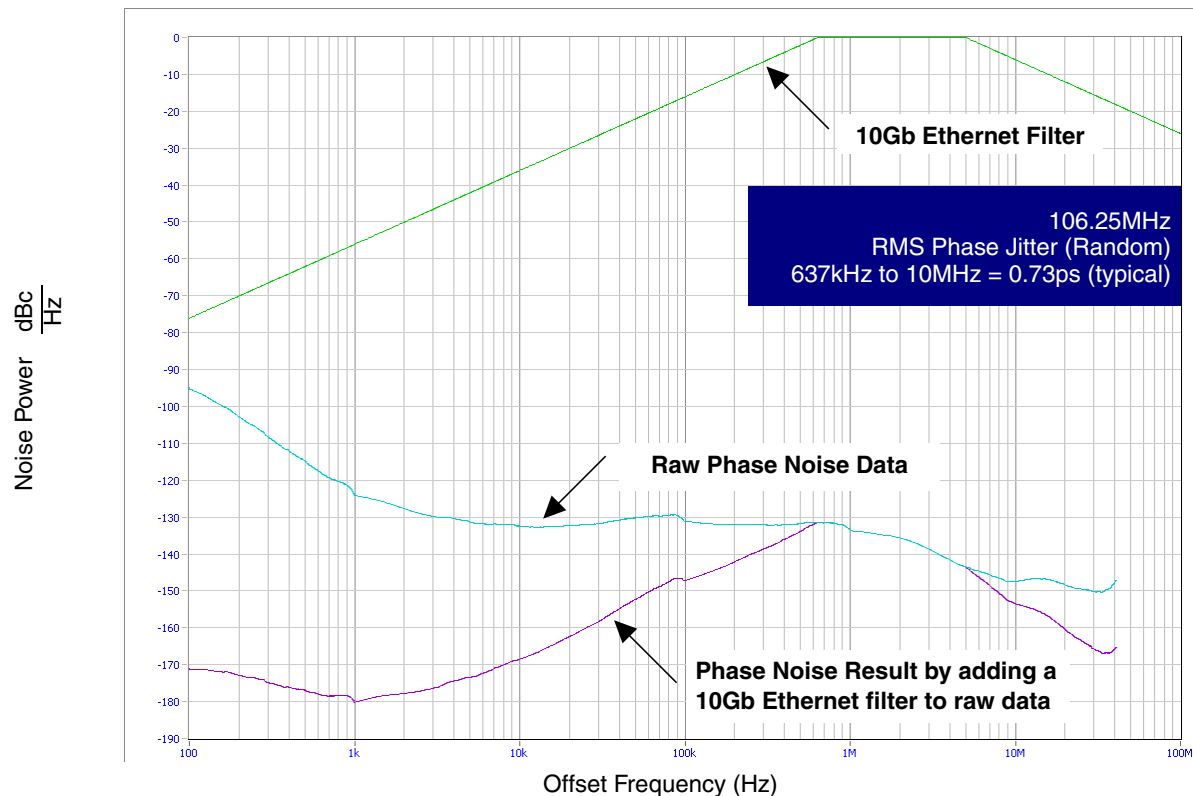




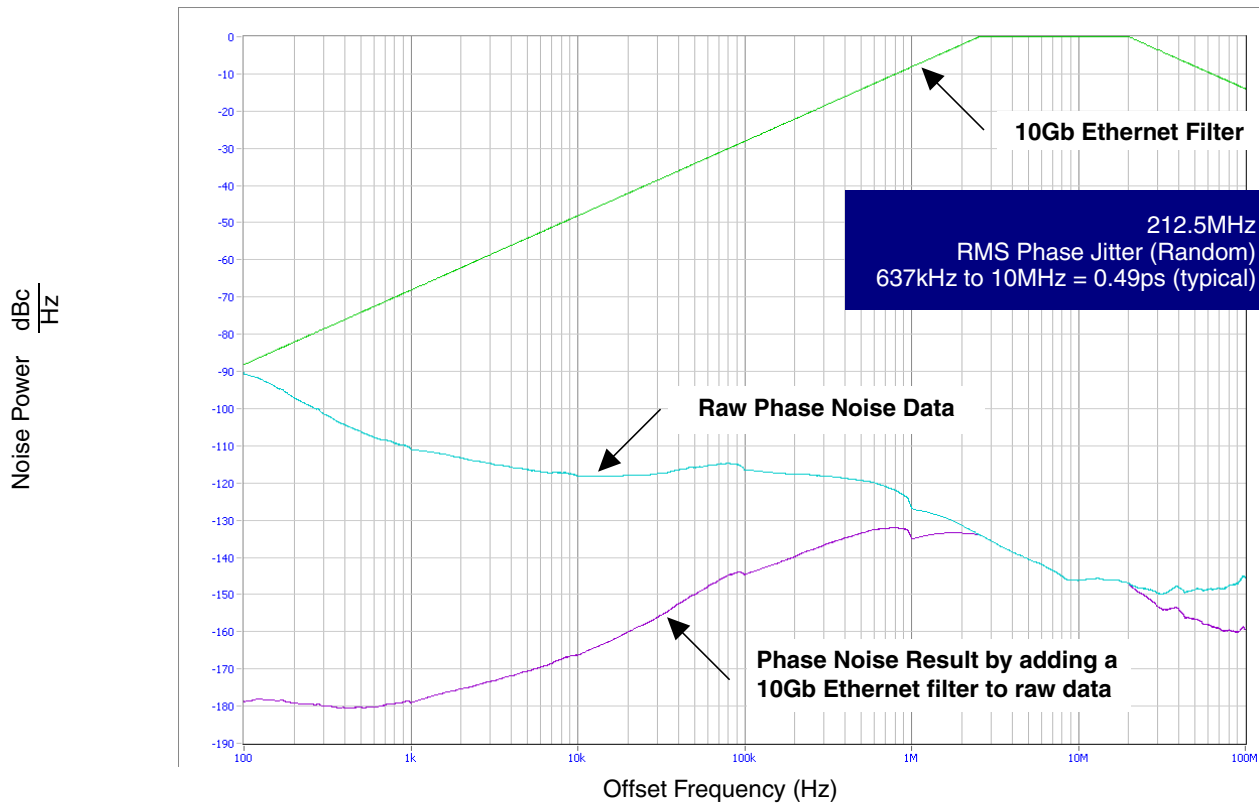
## Typical Phase Noise at 106.25MHz ( $V_{DD} = V_{DDO} = 3.3V$ )



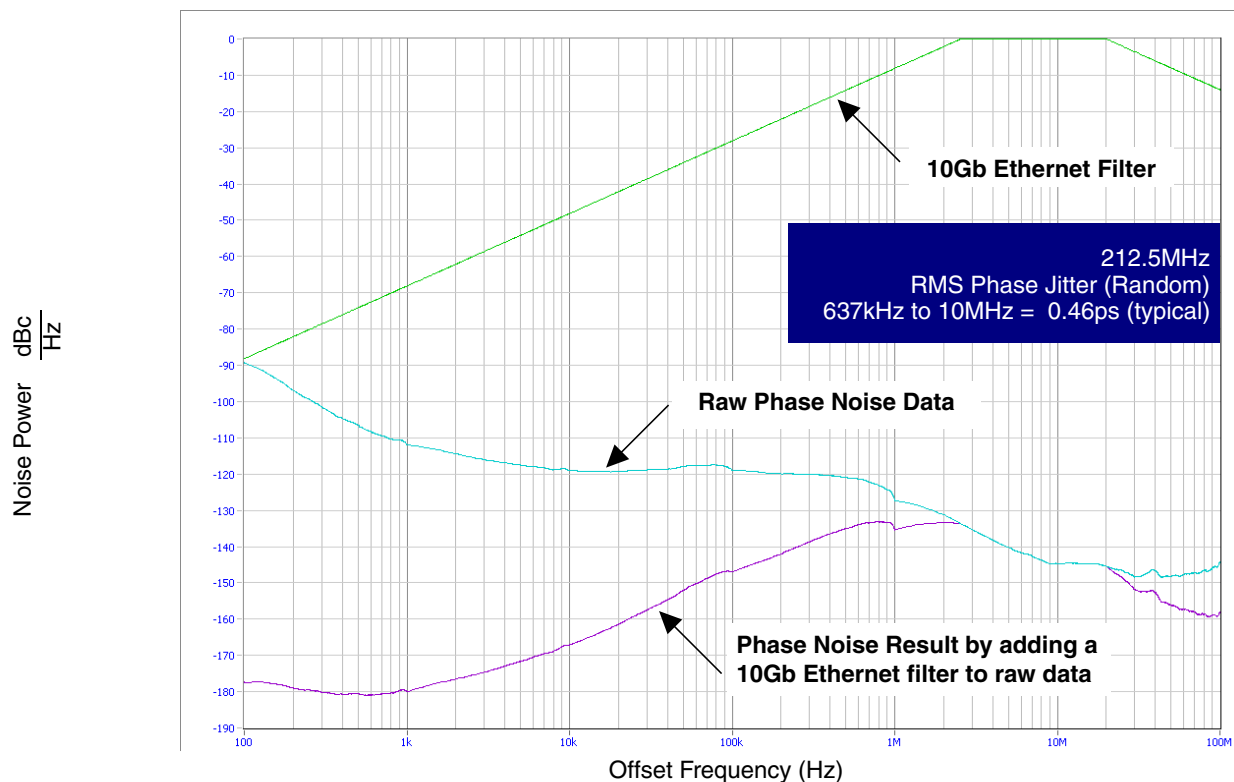
## Typical Phase Noise at 106.25MHz ( $V_{DD} = 3.3V, V_{DDO} = 2.5V$ )



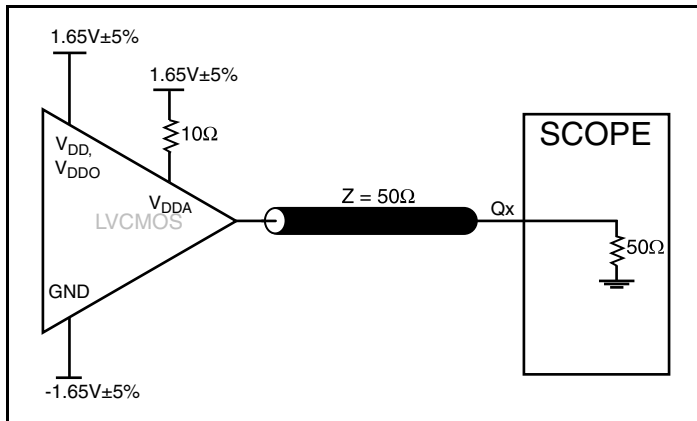
## Typical Phase Noise at 212.5MHz ( $V_{DD} = V_{DDO} = 3.3V$ )



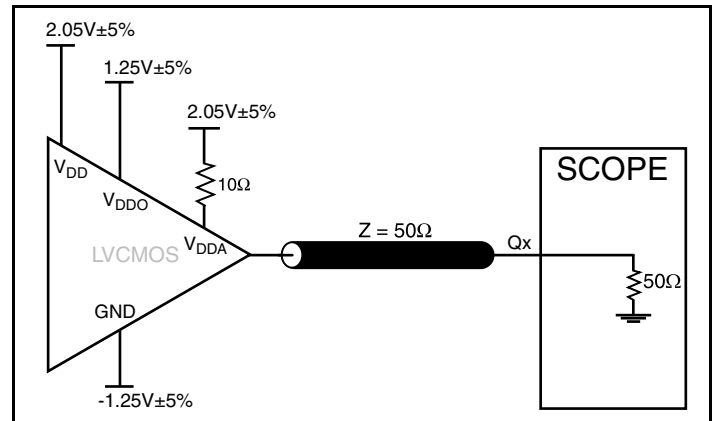
## Typical Phase Noise at 212.5MHz ( $V_{DD} = 3.3V, V_{DDO} = 2.5V$ )



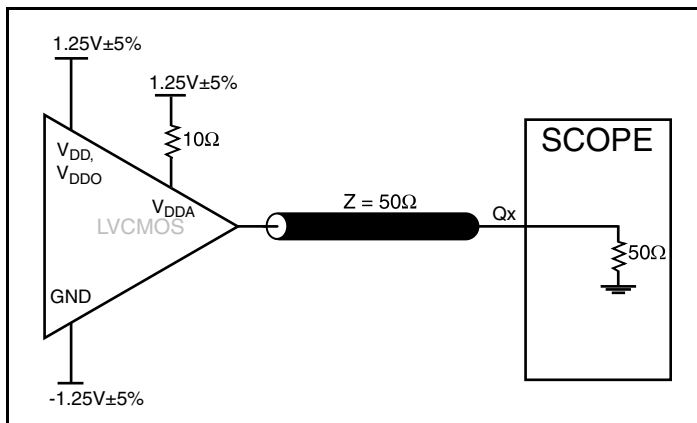
## Parameter Measurement Information



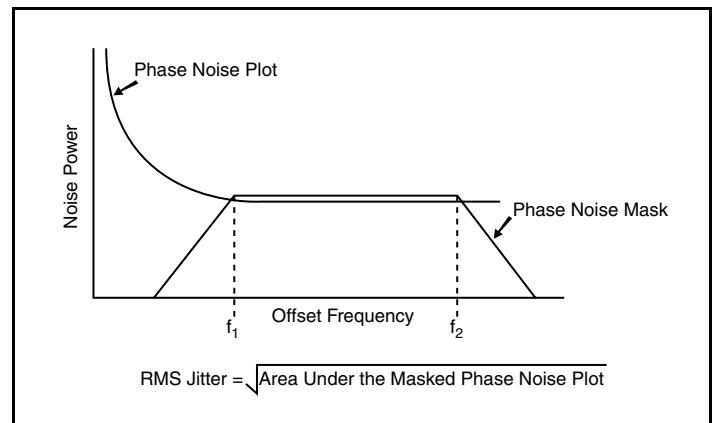
3.3V Core/3.3V LVCMOS Output Load AC Test Circuit



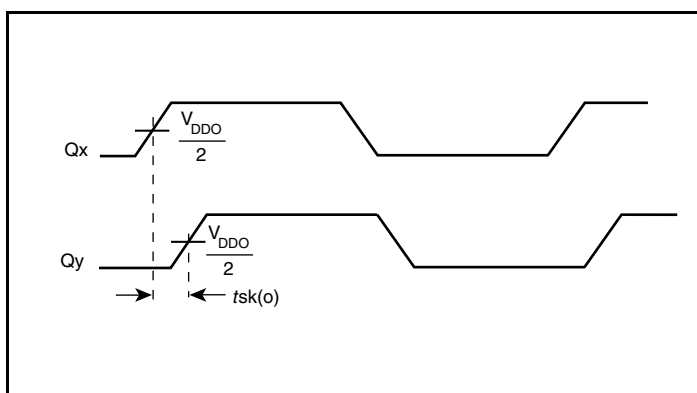
3.3V Core/2.5V LVCMOS Output Load AC Test Circuit



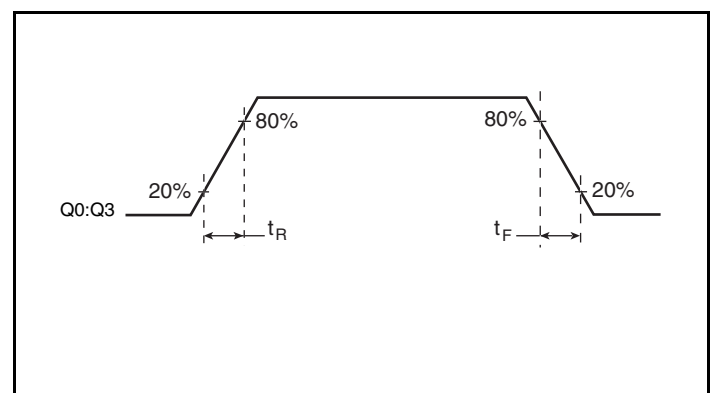
2.5V Core/2.5V LVCMOS Output Load AC Test Circuit



RMS Phase Jitter

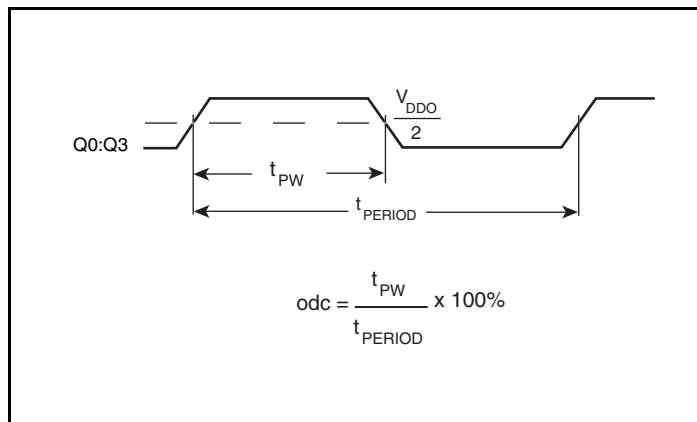


Output Skew



Output Rise/Fall Time

## Parameter Measurement Information, continued



Output Duty Cycle Pulse Width/Period

## Application Information

### Recommendations for Unused Input and Output Pins

#### Inputs:

##### Crystal Inputs

For applications not requiring the use of the crystal oscillator input, both XTAL\_IN and XTAL\_OUT can be left floating. Though not required, but for additional protection, a 1k $\Omega$  resistor can be tied from XTAL\_IN to ground.

##### REF\_CLK Input

For applications not requiring the use of the reference clock, it can be left floating. Though not required, but for additional protection, a 1k $\Omega$  resistor can be tied from the REF\_CLK to ground.

##### LVCMOS Control Pins

All control pins have internal pull-downs; additional resistance is not required but can be added for additional protection. A 1k $\Omega$  resistor can be used.

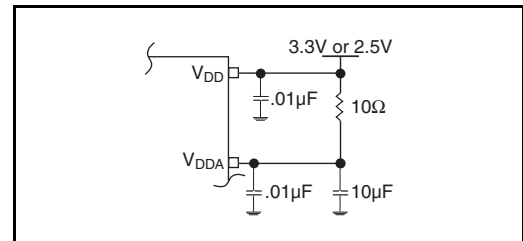
#### Outputs:

##### LVCMOS Outputs

All unused LVCMOS outputs can be left floating. We recommend that there is no trace attached.

### Power Supply Filtering Technique

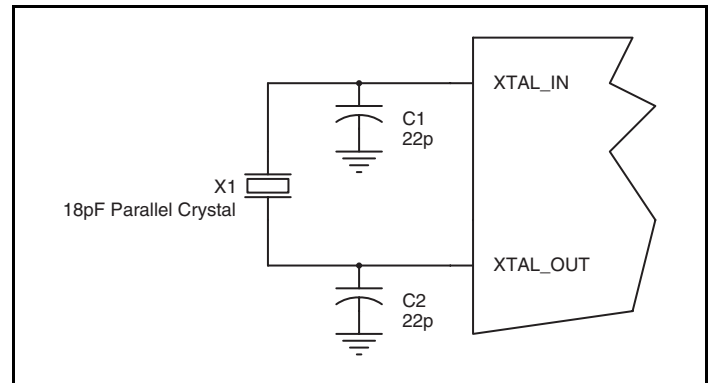
As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. To achieve optimum jitter performance, power supply isolation is required. The ICS840004I provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL.  $V_{DD}$ ,  $V_{DDA}$  and  $V_{DDO}$  should be individually connected to the power supply plane through vias, and 0.01 $\mu$ F bypass capacitors should be used for each pin. *Figure 1* illustrates this for a generic  $V_{DD}$  pin and also shows that  $V_{DDA}$  requires that an additional 10 $\Omega$  resistor along with a 10 $\mu$ F bypass capacitor be connected to the  $V_{DDA}$  pin.



**Figure 1. Power Supply Filtering**

## Crystal Input Interface

The ICS840004I has been characterized with 18pF parallel resonant crystals. The capacitor values shown in *Figure 2* below were determined using a 26.5625MHz, 18pF parallel resonant crystal and were chosen to minimize the ppm error.

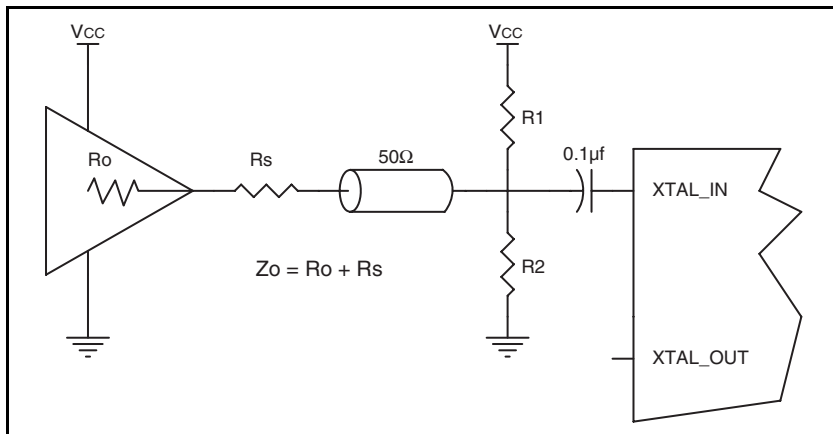


**Figure 2. Crystal Input Interface**

## LVCMOS to XTAL Interface

The XTAL\_IN input can accept a single-ended LVCMOS signal through an AC coupling capacitor. A general interface diagram is shown in *Figure 3*. The XTAL\_OUT pin can be left floating. The input edge rate can be as slow as 10ns. For LVCMOS inputs, it is recommended that the amplitude be reduced from full swing to half swing in order to prevent signal interference with the power rail and to reduce noise. This configuration requires that the output impedance of the driver ( $R_o$ ) plus the series resistance ( $R_s$ ) equals

the transmission line impedance. In addition, matched termination at the crystal input will attenuate the signal in half. This can be done in one of two ways. First,  $R_1$  and  $R_2$  in parallel should equal the transmission line impedance. For most 50Ω applications,  $R_1$  and  $R_2$  can be 100Ω. This can also be accomplished by removing  $R_1$  and making  $R_2$  50Ω. By overdriving the crystal oscillator, the device will be functional, but note, the device performance is guaranteed by using a quartz crystal.



**Figure 3. General Diagram for LVCMOS Driver to XTAL Input Interface**

## Schematic Example

Figure 4 shows a schematic example of the ICS840004I. An example of LVCMOS termination is shown in this schematic. Additional LVCMOS termination approaches are shown in the LVCMOS Termination Application Note. In this example, an 18pF parallel resonant 26.5625MHz crystal is used. The C1= 22pF and C2 = 22pF

are recommended for frequency accuracy. For different board layouts, the C1 and C2 may be slightly adjusted for optimizing frequency accuracy. The 1k $\Omega$  pullup or pulldown resistors can be used for the logic control input pins.

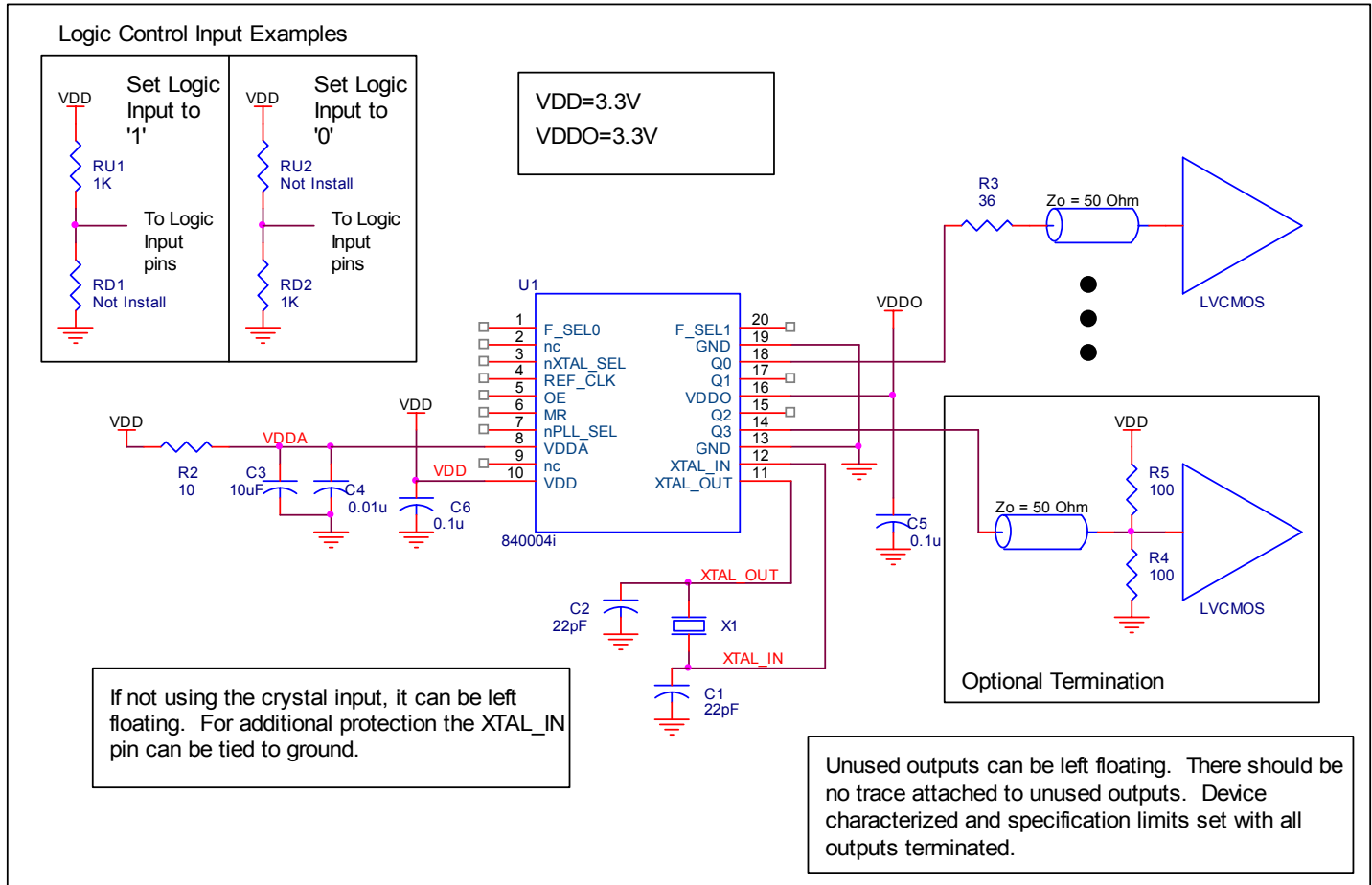


Figure 4. P.C. ICS840004I Schematic Example

## Reliability Information

Table 6.  $\theta_{JA}$  vs. Air Flow Table for a 20 Lead TSSOP

$\theta_{JA}$ by Velocity			
Linear Feet per Minute	0	200	500
Single-Layer PCB, JEDEC Standard Test Boards	114.5°C/W	98.0°C/W	88.0°C/W
Multi-Layer PCB, JEDEC Standard Test Boards	73.2°C/W	66.6°C/W	63.5°C/W

NOTE: Most modern PCB designs use multi-layered boards. The data in the second row pertains to most designs.

## Transistor Count

The transistor count for ICS840004I: 3796

## Package Outline and Package Dimensions

Package Outline - G Suffix for 20 Lead TSSOP

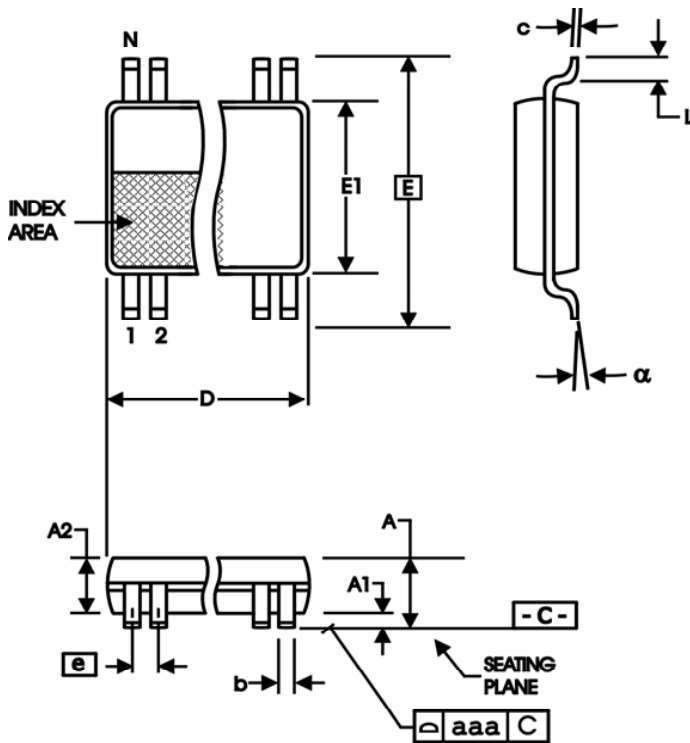


Table 7. Package Dimensions for 20 Lead TSSOP

All Dimensions in Millimeters		
Symbol	Minimum	Maximum
N	20	
A		1.20
A1	0.05	0.15
A2	0.80	1.05
b	0.19	0.30
c	0.09	0.20
D	6.40	6.60
E	6.40 Basic	
E1	4.30	4.50
e	0.65 Basic	
L	0.45	0.75
$\alpha$	0°	8°
aaa		0.10

Reference Document: JEDEC Publication 95, MO-153



## Ordering Information

**Table 8. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
840004BGI	ICS840004BGI	20 Lead TSSOP	Tube	-40°C to 85°C
840004BGIT	ICS840004BGI	20 Lead TSSOP	2500 Tape & Reel	-40°C to 85°C
840004BGILF	ICS840004BIL	20 Lead "Lead-Free" TSSOP	Tube	-40°C to 85°C
840004BGILFT	ICS840004BIL	20 Lead "Lead-Free" TSSOP	2500 Tape & Reel	-40°C to 85°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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## Revision History Sheet

Rev	Table	Page	Description of Change	Date
B	T5A - T5C	5 - 7	AC Characteristics - Changed Output Rise/Fall Time and Output Duty Cycle specs. Corrected fOUT FSEL = 10 from 156.25MHz typical to 106.25MHz and FSEL = 11 from 106.25MHz typical to 53.125MHz.	7/6/09
	T8	17	Ordering Information Table, changed revision from "A" to "B". Converted datasheet format.	



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